## Assessing Arctic Sea Ice Thickness using Wavelets

Don Percival

Applied Physics Laboratory University of Washington, Seattle

overheads for talk available at

http://faculty.washington.edu/dbp/talks.html

# Overview

- thickness of Arctic sea ice is subject of ongoing scientific interest
- seminar will discuss
  - role of thickness distributions
  - data available to evaluate changes in distributions
  - simplification based upon notion of ice types
  - Haar wavelet variance and its potential role in
    - \* evaluating changes
    - \* providing additional insights into Arctic sea ice variability
- work in progress with Yanling Yu, Polar Science Center, APL (future work will involve Mike Keim, QERM)

# **Ice Thickness Distributions**

- basic description of Arctic sea ice is distribution of its thickness
- one distribution for entire Arctic basin of less interest than ones
  - localized to specific regions
  - limited to certain time spans
- good physical reasons to hypothesize that distributions are
  - not uniform in space
  - not invariant with time
- inhomogeneities in space and time due to many factors
  - thermodynamic processes control ice growth and melt
  - winds and currents drive ice motion, creating pressure ridges or areas of open water and thin ice

# **Ice Thickness Profiles**



- 750 meter portion of ice thickness profile h(l) measured by a submarine near North Pole in April, 1991
- l is distance in meters along submarine's transect
- measurements are ice drafts, converted to thickness  $(\times 1.12)$
- entire profile extends over 50 km (one data point each meter)

## Submarine Tracks 1976–97



- left-hand plot shows spring (April–May) cruises
- right-hand plot shows fall (Sept–Oct) cruises
- possibility of more data eventually becoming available

## **Estimated Ice Thickness Distributions: I**



• above give estimates of ice thickness distributions g(h) based on transects near the North Pole, suggesting a thinning of ice from 1991 to 1994, but are differences statistically significant?

## **Estimated Ice Thickness Distributions: II**



- 8 more estimated distributions (4 regions & 2 time periods)
- note: not well-modeled by normal (Gaussian) distribution

# Statistical Assessment of Thickness Distributions: I

- while visual differences are suggestive, little definitive is known about spatial-temporal properties of ice thickness distributions
- need to understand if observed differences are due primarily to
  - 1. spatial variability that is consistent from year to year
  - 2. spatial variability that is changing significantly over time and hence represents important climate changes or
  - 3. sampling variations that are consistent with the amount of available data
- standard statistical methodology for evaluating null hypothesis that two samples of data come from same distribution assumes independent samples

# **Statistical Assessment of Thickness Distributions: II**



- $\bullet$  independence assumption unrealistic profiles h(l) are highly autocorrelated
- since histograms are markedly non-Gaussian, have difficult statistical problem of assessing changes in estimated distributions for correlated data from unknown null distribution g(h)

# Simplification via Ice Type Distributions: I



- can simplify problem considerably by binning data according to physically meaningful ice types:
  - 1. leads and new ice, for which h(l) < 0.3 m;
  - 2. first year ice, for which 0.3 m  $\leq h(l) < 2$  m;
  - 3. medium multiyear ice, for which 2 m  $\leq h(l) < 5$  m; and
  - 4. ridged ice, for which  $h(l) \ge 5$  m
- horizontal red lines indicate binning into ice types

### Simplification via Ice Type Distributions: II

- let  $h_i^{(l)}$  and  $h_i^{(u)}$  be the lower and upper limits for the *i*th ice type (with  $h_1^{(l)} = 0$  and  $h_4^{(u)} = \infty$ )
- define an indicator series for ith ice type as

$$I_i(l) = \begin{cases} 1, \text{ if } h_i^{(l)} \le h(l) < h_i^{(u)}; \text{ and} \\ 0, \text{ otherwise.} \end{cases}$$

## Simplification via Ice Type Distributions: III



• bottom 4 plots show indicator series (these are binary valued)

# Simplification via Ice Type Distributions: IV



- binned data described by 4 values (constrained to sum to 1)
- ice type distributions coarser than original ice thickness distributions, but former captures essence of latter

# Assessing Changes in Ice Type Distributions: I

- after binning, question of significance of changes still remains, but can be tackled using the following ideas
- by construction, area under an estimated ice type distribution between  $h_i^{(l)}$  and  $h_i^{(u)}$  is observed proportion  $\hat{p}_i$  of occurrences of the *i*th ice type in h(l)
- proportion  $\hat{p}_i$  is estimator of corresponding theoretical quantity

$$p_i = \int_{h_i^{(l)}}^{h_i^{(u)}} g(h) \, dh$$

### Assessing Changes in Ice Type Distributions: II

• observed proportion  $\hat{p}_i$  is just sample mean of *i*th indicator series  $I_i(l)$ :

$$\hat{p}_i = \frac{1}{N} \sum_{l=0}^{N-1} I_i(l),$$

where N is # of measurements in profile (typically > 50,000) • corresponding sample variance for  $I_i(l)$  is given by

$$\hat{\sigma}_i^2 = \frac{1}{N} \sum_{l=0}^{N-1} (I_i(l) - \hat{p}_i)^2 = \hat{p}_i(1 - \hat{p}_i).$$

# Assessing Changes in Ice Type Distributions: III

• if  $I_i(l)$ , l = 0, ..., N - 1, were a realization of N independent binary-valued random variables, could compute an approximate 95% confidence interval for  $p_i$  based upon an estimate of the variance of  $\hat{p}_i$ :

$$\operatorname{var}\{\hat{p}_i\} \approx \frac{\hat{\sigma}_i^2}{N} = \frac{\hat{p}_i(1-\hat{p}_i)}{N},$$

- independence does not hold due to autocorrelation, so need to determine correlation structure of indicator series  $I_i(l)$
- can quantify correlation structure using wavelets

## **Decomposing Sample Variance of 'Time' Series**

- let  $X_0, X_1, \ldots, X_{N-1}$  represent a 'time' series with N values (for sea ice, 'time' is actually distance along a transect)
- let  $\overline{X}$  denote sample mean of  $X_t$ 's:  $\overline{X} \equiv \frac{1}{N} \sum_{t=0}^{N-1} X_t$
- let  $\hat{\sigma}_X^2$  denote sample variance of  $X_t$ 's:

$$\hat{\sigma}_X^2 \equiv \frac{1}{N} \sum_{t=0}^{N-1} \left( X_t - \overline{X} \right)^2$$

- can quantify certain properties of  $X_t$  by an analysis of variance, i.e., by decomposing (breaking up)  $\hat{\sigma}_X^2$  into pieces
- analysis of variance using wavelets based upon differences between adjacent averages over certain 'scales'

# Notion of Scale

- scale  $\tau$  refers to width of an interval (e.g., chunch of a transect)
- scale-based analysis looks at averages over intervals of width  $\tau$ :

$$\overline{X}_t(\tau) \equiv \frac{1}{\tau} \sum_{l=0}^{\tau-1} X_{t-l}$$

• localized average of  $X_t$  and its  $\tau - 1$  prior values

• 
$$\overline{X}_t(1) = X_t$$
 is scale 1 'average'

• 
$$\overline{X}_{N-1}(N) = \overline{X}$$
 is scale N average

### Wavelet Coefficients and Filters

- wavelet coefficients tell us about variations in adjacent averages
- use wavelet filter to create wavelet coefficients
- given  $X_0, X_1, \ldots, X_{N-1}$ , define wavelet coefficients via  $\widetilde{W}_{j,t} \equiv \sum_{l=0}^{L_j-1} \widetilde{h}_{j,l} X_{t-l \mod N}, \quad t = 0, 1, \ldots, N-1,$ where  $\widetilde{h}_{j,l}$  is a wavelet filter with  $L_j$  coefficients, and  $X_{t-l \mod N} = X_t$  if  $0 \le t-l \le N-1$   $X_{-1 \mod N} = X_{N-1}$

$$X_{-2 \mod N} = X_{N-2}$$
 etc ('circularity')

• index j specifies associated scale as  $\tau_j \equiv 2^{j-1}, j = 1, 2, \ldots$ ; i.e., scales are powers of two  $(1, 2, 4, 8, \ldots)$ 

### Haar Wavelet Filters

• Haar wavelet filters  $\tilde{h}_{j,l}$  for scales indexed by  $j = 1, \ldots, 7$ 



positive & 1 negative coefficient
positive & 2 negative coefficients
4 & 4

#### Haar Wavelet Coefficients: I

• consider how  $\widetilde{W}_{1,1} = \sum_l \widetilde{h}_{1,l} X_{1-l \mod N}$  is formed (N = 16):



• similar interpretation for  $\widetilde{W}_{1,15} = \sum_{l} \widetilde{h}_{1,l} X_{15-l \mod N}$ :



### Haar Wavelet Coefficients: II

• now consider form of  $\widetilde{W}_{2,3} = \sum_l \widetilde{h}_{2,l} X_{3-l \mod N}$ :



- similar interpretation for  $\widetilde{W}_{2,4}, \widetilde{W}_{2,5}, \ldots, \widetilde{W}_{2,15}$
- note:  $W_{2,0}, W_{2,1}$  and  $W_{2,2}$  aren't proportional to differences of adjacent averages (called 'boundary' coefficients)

## Haar Wavelet Coefficients: III

• 
$$\widetilde{W}_{3,7} = \sum_{l} \widetilde{h}_{3,l} X_{7-l \mod N}$$
 takes the following form:

$$\tilde{h}_{3,l} \qquad \qquad \text{product} \qquad \text{sum} \propto \overline{X}_7(4) - \overline{X}_3(4)$$

- Haar wavelet coefficients  $\widetilde{W}_{j,t}$  for scale  $\tau_j = 2^{j-1}$  proportional to  $\overline{X}_t(\tau_j) \overline{X}_{t-\tau_j}(\tau_j)$ . i.e., to change in adjacent  $\tau_j$  averages
  - change measured by simple first difference
  - average is localized sample mean
  - if  $\widetilde{W}_{j,t}^2$  small, not much variation over scale  $\tau_j$ - if  $\widetilde{W}_{j,t}^2$  large, lot of variation over scale  $\tau_j$

### **Empirical Wavelet Variance**

• define empirical wavelet variance for scale  $\tau_j$  as

$$\tilde{\nu}_X^2(\tau_j) \equiv \frac{1}{N} \sum_{t=0}^{N-1} \widetilde{W}_{j,t}^2$$

• if  $N = 2^J$ , obtain analysis (decomposition) of sample variance:

$$\hat{\sigma}_X^2 = \frac{1}{N} \sum_{t=0}^{N-1} \left( X_t - \overline{X} \right)^2 = \sum_{j=1}^J \tilde{\nu}_X^2(\tau_j)$$

(if N not a power of 2, can still obtain an analysis of variance to a given level  $J_0$ , but have component due to 'scaling' filter)

• interpretation:  $\tilde{\nu}_X^2(\tau_j)$  is portion of  $\hat{\sigma}_X^2$  due to changes in averages over scale  $\tau_j$ ; i.e., 'scale by scale' analysis of variance

#### **Example of Empirical Wavelet Variance**

• wavelet variances for time series  $X_t$  and  $Y_t$  of length N = 16, each with zero sample mean and same sample variance



### Second Example of Empirical Wavelet Variance

• top: subtidal sea level series  $X_t$  (blue line shows scale of 16)



• bottom: empirical wavelet variances  $\tilde{\nu}_X^2(\tau_j)$ 

### **Theoretical Wavelet Variance: I**

- now assume  $X_t$  is a real-valued random variable (RV)
- let  $X_t, t \in \mathbb{Z}$  denote a stochastic process, i.e., collection of RVs indexed by 'time' t (here  $\mathbb{Z}$  denotes the set of all integers)
- filter  $X_t$  to create new stochastic process:

$$\overline{W}_{j,t} \equiv \sum_{l=0}^{L_j - 1} \tilde{h}_{j,l} X_{t-l}, \quad t \in \mathbb{Z},$$

which should be contrasted with

$$\widetilde{W}_{j,t} \equiv \sum_{l=0}^{L_j-1} \widetilde{h}_{j,l} X_{t-l \mod N}, \quad t = 0, 1, \dots, N-1$$

### **Theoretical Wavelet Variance: II**

- if Y is any RV, let  $E\{Y\}$  denote its expectation
- let var {Y} denote its variance: var {Y}  $\equiv E\{(Y E\{Y\})^2\}$
- definition of wavelet variance:

$$\nu_X^2(\tau_j) \equiv \operatorname{var} \{ \overline{W}_{j,t} \},\$$

with conditions on  $X_t$  so that var  $\{\overline{W}_{j,t}\}$  exists, is finite and does not depend on t

•  $\nu_X^2(\tau_j)$  well-defined for stationary processes, so let's review concept of stationarity

### **Definition of a Stationary Process**

• if U and V are two RVs, denote their covariance by  $\operatorname{cov} \{U, V\} = E\{(U - E\{U\})(V - E\{V\})\}$ 

• stochastic process  $X_t$  called stationary if

 $-E\{X_t\} = \mu_X \text{ for all } t, \text{ i.e., constant independent of } t$  $-\cos\{X_t, X_{t+\tau}\} = s_{X,\tau}, \text{ i.e., depends on lag } \tau, \text{ but not } t$ 

•  $s_{X,\tau}, \tau \in \mathbb{Z}$ , is autocovariance sequence (ACVS)

•  $s_{X,0} = \operatorname{cov}\{X_t, X_t\} = \operatorname{var}\{X_t\}$ ; i.e., variance same for all t

#### **Example of a Stationary Process: White Noise**

- simplest example of a stationary process is 'white noise'
- process  $X_t$  said to be white noise if
  - it has a constant mean  $E\{X_t\} = \mu_X$
  - it has a constant variance var  $\{X_t\} = \sigma_X^2$
  - $-\cos \{X_t, X_{t+\tau}\} = 0$  for all t and nonzero  $\tau$ ; i.e., distinct RVs in the process are uncorrelated
- ACVS for white noise takes a very simple form:

$$s_{X,\tau} = \operatorname{cov} \{X_t, X_{t+\tau}\} = \begin{cases} \sigma_X^2, & \tau = 0; \\ 0, & \text{otherwise} \end{cases}$$

#### Wavelet Variance for Stationary Processes

• for stationary processes, wavelet variance decomposes var  $\{X_t\}$ :

$$\sum_{j=1}^{\infty} \nu_X^2(\tau_j) = \operatorname{var} \{X_t\}$$

(above result similar to one for sample variance)

- $\nu_X^2(\tau_j)$  is thus contribution to var  $\{X_t\}$  due to scale  $\tau_j$
- example: for a white noise process, have

$$\nu_X^2(\tau_j) = \frac{\operatorname{var} \{X_t\}}{2^j} = \frac{\operatorname{var} \{X_t\}}{2\tau_j} \propto \tau_j^{-1},$$

so largest contribution to var  $\{X_t\}$  is at smallest scale  $\tau_1$ 

# Fractionally Differenced (FD) Processes: I

- as another example, consider wavelet variance for FD processes (Granger & Joyeux, 1980; Hosking, 1981)
- FD processes determined by 2 parameters  $-\infty < \delta < \infty$  &  $\sigma_{\epsilon}^2 > 0$  (relatively unimportant)
- if  $\delta < 1/2$ , FD process  $X_t$  is stationary, and, in particular,
  - reduces to white noise if  $\delta = 0$
  - has 'long range' dependence if  $\delta>0;$  i.e.,  $s_{X,\tau}>0$  and does not decrease to zero rapidly
  - is 'antipersistent' if  $\delta < 0$  (i.e.,  $\operatorname{cov} \{X_t, X_{t+1}\} < 0$ )

# Fractionally Differenced (FD) Processes: II

• at large scales, have

$$\nu_X^2(\tau_j) \approx C \tau_j^{2\delta - 1}$$

• thus

$$\log\left(\nu_X^2(\tau_j)\right) \approx \log\left(C\right) + (2\delta - 1)\log\left(\tau_j\right),$$

so a log/log plot of  $\nu_X^2(\tau_j)$  vs.  $\tau_j$  looks approximately linear with slope  $2\delta - 1$  for  $\tau_j$  large enough

• for white noise, have  $\delta = 0$ ,  $\nu_X^2(\tau_j) = C\tau_j^{-1}$  and hence

$$\log\left(\nu_X^2(\tau_j)\right) = \log\left(C\right) - \log\left(\tau_j\right),$$

## LA(8) Wavelet Variance for 2 FD Processes



- left-hand column:  $\nu_X^2(\tau_j)$  versus  $\tau_j$
- right-hand: realization of length N = 256 from each FD process
- note: slope on log/log plot would be -1 for uncorrelated data (white noise)

### Haar Wavelet Analysis of Ice Type Series: I

- let  $W_{i;j,l}$  denote Haar wavelet coefficient for *i*th ice type and scale  $\tau_j = 2^{j-1}$  meters at location along transect indexed by l
- coefficient is proportional to difference of adjacent sample means:

$$W_{i;j,l} \propto \frac{1}{\tau_j} \sum_{m=0}^{\tau_j - 1} I_i(l-m) - \frac{1}{\tau_j} \sum_{n=0}^{\tau_j - 1} I_i(l-\tau_j - n),$$

- because  $I_i(l)$  is binary-valued,  $W_{i;j,l}$  has simple and intuitively appealing interpretation: it is proportional to *differences* in percentage of *i*th ice type between adjacent parts of the ice thickness profile, with each part being of scale (length)  $\tau_j$ .
- if  $W_{i;j,l}^2$  is small, ice type percentage is stable, i.e., not varying much between adjacent parts of scale  $\tau_j$

### Haar Wavelet Analysis of Ice Type Series: II



• estimated wavelet variances based upon averaging available  $W_{i;j,l}^2$ • red line has slope of -1 (appropriate for white noise)

## Haar Wavelet Analysis of Ice Type Series: III

- wavelet variance curves are basically unimodal
- location of peak gives indication of 'characteristic scale' (e.g.,  $\approx 256$  m and 32 m for types 1 and 4)
- conjecture: can use characteristic scale and rate of decay of curve as  $\tau_i$  gets large to assess variability in  $\hat{p}_i$  via

$$\operatorname{var}\{\hat{p}_i\} \approx \frac{\hat{p}_i(1-\hat{p}_i)}{N_e^{-\beta}}$$

- $N_e \propto N$  is 'effective sample size,' with constant of proportionality being related to the characteristic scale
- rate at which  $\operatorname{var}\{\hat{p}_i\}$  decreases to zero as N increases is determined by  $\beta$ , which is the slope of  $\log(\hat{\nu}_i^2(\tau_j))$  versus  $\log(\tau_j)$  over large  $\tau$

# **Future Work**

- work out statistical theory for testing null hypothesis of constant ice type distribution
- investigate relationship between characteristic scales and physical processes
- look at spatial and temporal variations in distributions and characteristics scales
- thanks for the invitation to speak!